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## Conductance of perovskite oxide thin films and interfaces

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# **Conductance of perovskite oxide thin films and interfaces**

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door

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geboren te Lahore, Pakistan  
op 23 augustus 1978

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**Cover Illustration:** A high resolution TEM micrograph of the interface between two band insulators LaAlO<sub>3</sub> and SrTiO<sub>3</sub>.

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**To my mother**



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